

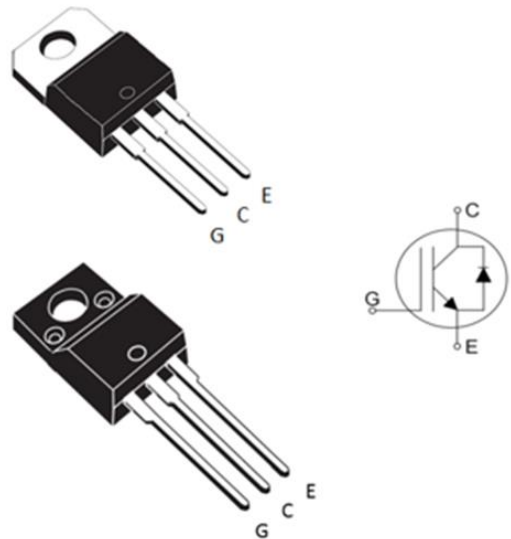
FEATURES

- High breakdown voltage to 650V for improved reliability
- Trench-Stop Technology offering :
 - Very tight parameter distribution
 - High ruggedness, temperature stable behavior
 - High speed switching
 - Low switching losses
 - Low V_{CEsat}
 - Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}

V_{CE}	650	V
I_C	15	A
$V_{CE(sat)}$ $I_C=15A$	1.7	V

APPLICATION

- Soft switching applications
- Air conditioning
- Motor drive inverter
- Converter with high switching frequency



Product	Package	Packaging
YGF15N65TSA1	TO-220F	Tube
YGP15N65TSA1	TO-220	Tube

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter Breakdown Voltage, $T_j \geq 25^\circ\text{C}$	V_{CE}	650	V
DC collector current, limited by T_{jmax} $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	I_C	30 15	A
Diode Forward current, limited by T_{jmax} $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$	I_F	30 15	A
Continuous Gate-emitter voltage	V_{GE}	± 25	V
Transient Gate-emitter voltage ($t_p \leq 10\mu\text{s}, D < 0.01$)	V_{GE}	± 30	V
Turn off safe operating area $V_{CE} \leq 650\text{V}, T_j \leq 175^\circ\text{C}, t_p = 1\mu\text{s}$	-	45	A
Pulsed Collector Current $V_{GE} = 15\text{V}, t_p$ limited by T_{jmax}	I_{CM}	45	A
Diode Pulsed Current, t_p limited by T_{jmax}	I_{Fpuls}	30	A
Power dissipation, $T_C = 25^\circ\text{C}$	P_{tot}	TO220 150	W
Power dissipation, $T_C = 100^\circ\text{C}$		TO220F 39	
		75 20	
Max. Junction Temperature	$T_{J,max}$	175	$^\circ\text{C}$
Operating junction temperature	$T_{J,op}$	$-40 \dots +175$	$^\circ\text{C}$
Storage temperature	T_{stg}	$-55 \dots +150$	$^\circ\text{C}$
Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s	-	260	$^\circ\text{C}$
Mounting torque, M3 screw Maximum of mounting processes: 3	M	0.6	Nm

Thermal Resistance

Parameter	Symbol	TO-220F	TO-220	Unit
IGBT thermal	$R_{\theta(j-c)}$	3.8	1	K/W
Diode thermal	$R_{\theta(j-c)}$	4.2	2.1	K/W
Thermal resistance, junction -	$R_{\theta(j-a)}$	50	40	K/W

Electrical Characteristics of the IGBT ($T_j = 25^\circ\text{C}$ unless otherwise specified) :

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static						
Collector-Emitter breakdown voltage	$BV_{CES}^{①}$	$V_{GE}=0V, I_C=250\mu A$	650	-	-	V
Gate threshold voltage	$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C=500\mu A$	4.9	5.7	6.5	V
Collector-Emitter Saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=15A$ $T_j = 25^\circ\text{C}$ $T_j = 175^\circ\text{C}$	- -	1.65 2.0	2.15 -	V
Zero gate voltage collector current	I_{CES}	$V_{CE}=650V, V_{GE}=0V$ $T_j = 25^\circ\text{C}$ $T_j = 175^\circ\text{C}$	- -	- -	40 1000	μA
Gate-emitter leakage current	I_{GES}	$V_{CE}=0V, V_{GE}= \pm 20V$	-	-	400	nA
Transconductance	g_{fs}	$V_{CE}=20V, I_C=15A$	-	10	-	S

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Dynamic						
Input capacitance	C_{ies}	$V_{CE} = 25V, V_{GE} = 0V,$ $f = 1\text{MHz}$	-	1308	-	pF
Output capacitance	C_{oes}		-	48	-	
Reverse transfer capacitance	C_{res}		-	13	-	
Gate charge total	Q_g	$V_{CC} = 520V, I_C=15A,$ $V_{GE} = 15V$	-	48	-	nC
Gate to emitter charge	Q_{ge}		-	12	-	
Gate to collector charge	Q_{gc}		-	21	-	
Internal Gate Resistance	$R_{G,int}$	$f = 1\text{MHz}$	-	1.5	-	Ω

Note:

① BV_{ces} testing without filter could damage the device. BV_{ces} is guaranteed by $I_{ces}@650V$ test

Switching Characteristic, Inductive Load

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Dynamic						
Turn-on Delay Time	$t_{d(on)}$	$T_j=25^{\circ}\text{C}$, $V_{CE} = 400\text{V}$, $I_C = 15\text{A}$, $V_{GE} = 0/15\text{V}$, $R_g=5\Omega$	-	6.17	-	ns
Rise Time	t_r		-	26.9	-	ns
Turn-off Delay Time	$t_{d(off)}$		-	38.2	-	ns
Fall Time	t_f		-	100.8	-	ns
Turn-on Energy	E_{on}		-	0.34	-	mJ
Turn-off Energy	E_{off}		-	0.23	-	mJ
Turn-on Delay Time	$t_{d(on)}$	$T_j=150^{\circ}\text{C}$, $V_{CE} = 400\text{V}$, $I_C = 15\text{A}$, $V_{GE} = 0/15\text{V}$, $R_g=5\Omega$	-	6.34	-	ns
Rise Time	t_r		-	27.7	-	ns
Turn-off Delay Time	$t_{d(off)}$		-	48.9	-	ns
Fall Time	t_f		-	172.3	-	ns
Turn-on Energy	E_{on}		-	0.39	-	mJ
Turn-off Energy	E_{off}		-	0.42	-	mJ

Electrical Characteristics of the DIODE

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Diode Forward Voltage	V_{FM}	$I_F=15\text{A}$ $T_j=25^{\circ}\text{C}$ $T_j=175^{\circ}\text{C}$	-	1.65 1.50	-	V
Reverse Recovery Time	T_{rr}	$T_j=25^{\circ}\text{C}$,	-	114	-	ns
Reverse Recovery Current	I_{rr}	$I_F= 15\text{A}$, $V_R = 400\text{V}$,	-	18.5	-	A
Reverse Recovery Charge	Q_{rr}	$di_F/dt = 790\text{A}/\mu\text{s}$	-	0.82	-	μC

Fig. 1 Output characteristic V_{CE} vs. I_C at 25°C

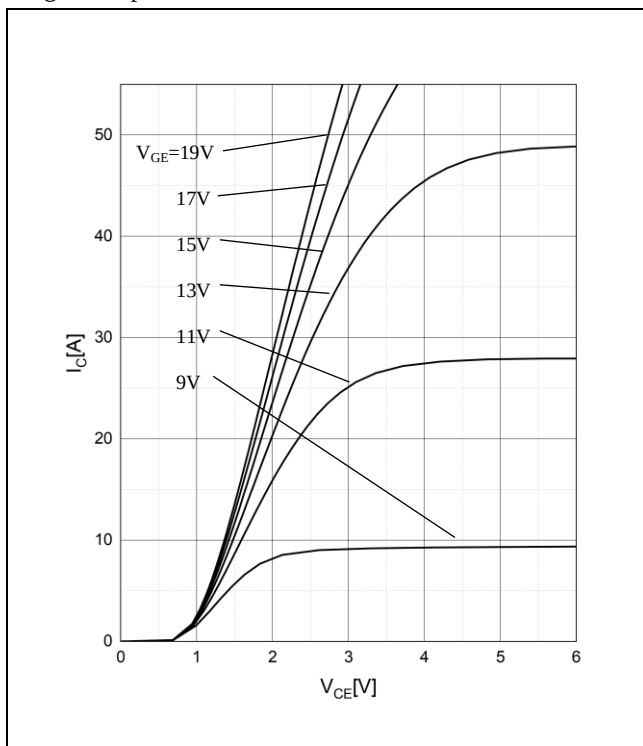


Fig. 2 Output characteristic V_{CE} vs. I_C at 175°C

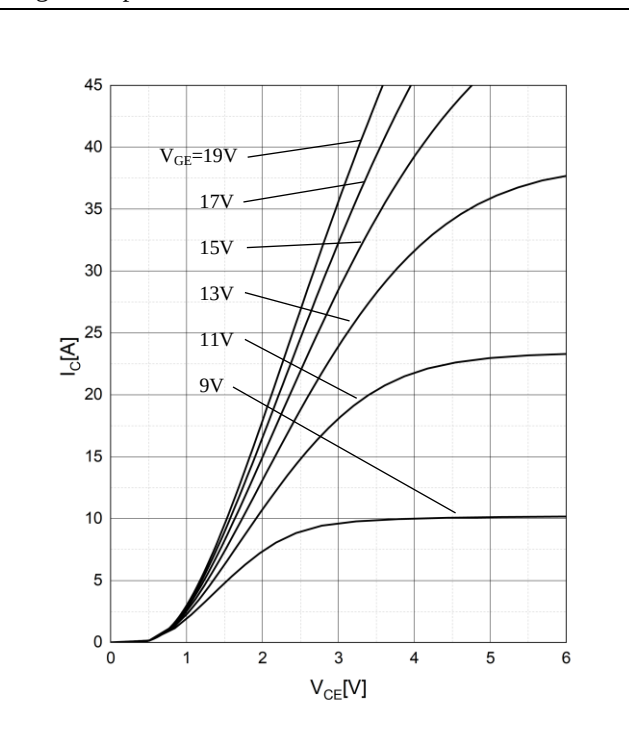


Fig. 3 Transfer characteristic V_{GE} vs. I_C

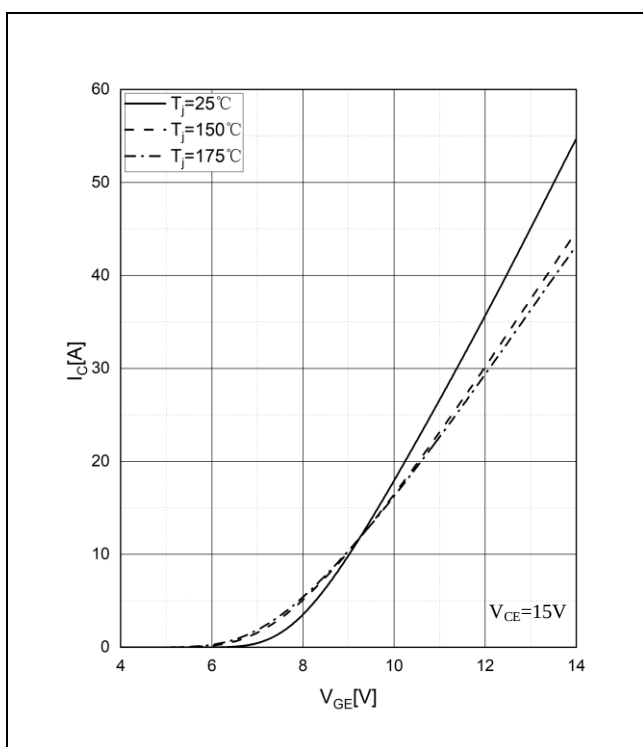


Fig. 4 Collector-emitter saturation voltage as a function of junction temperature V_{CEsat} vs. T_J

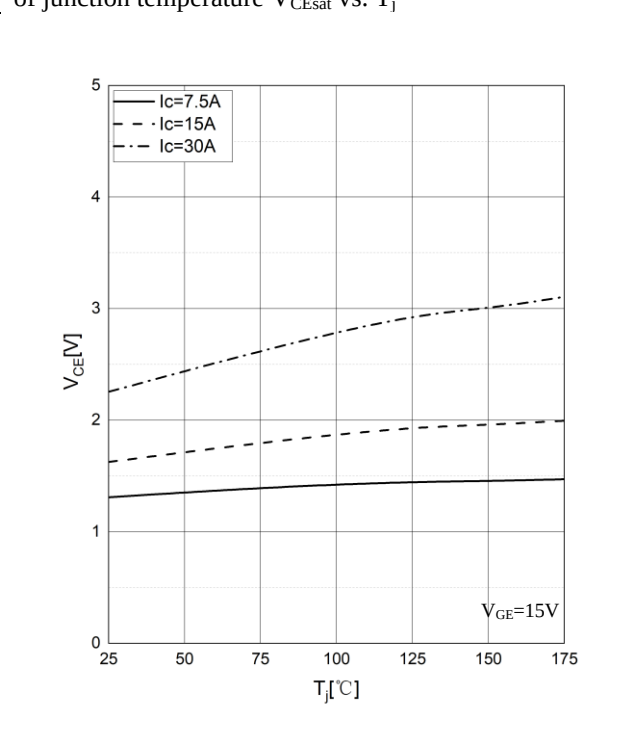


Fig. 5 Gate-emitter threshold voltage as a function of junction temperature $V_{GE(th)}$ vs. T_j

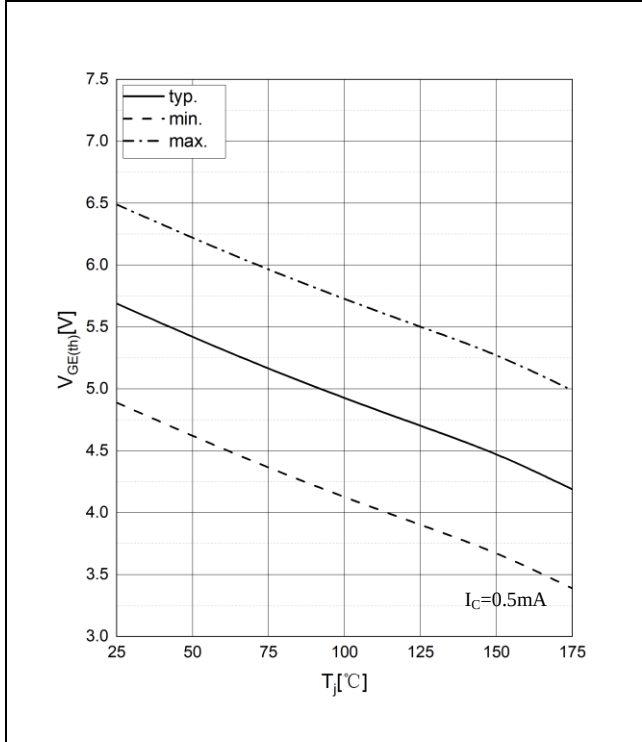


Fig. 6 Gate charge Q_G

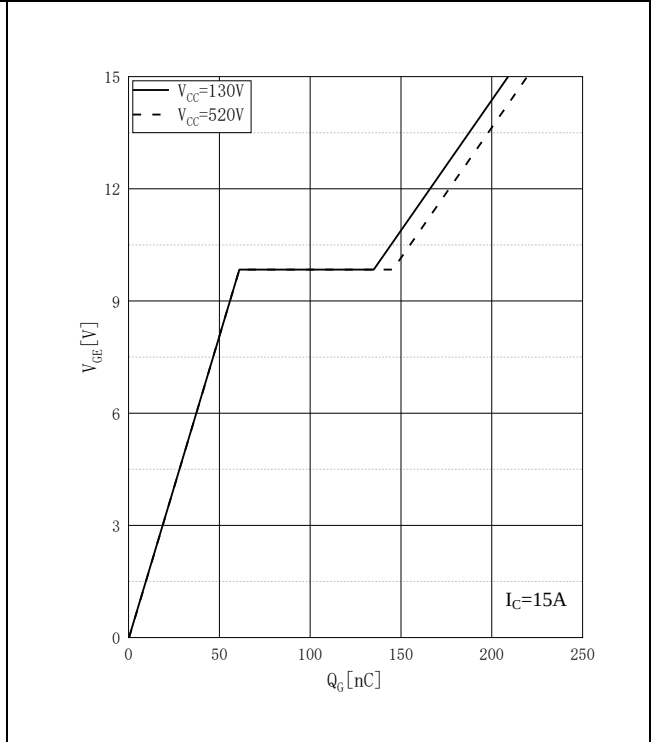


Fig. 7 Capacitance characteristic

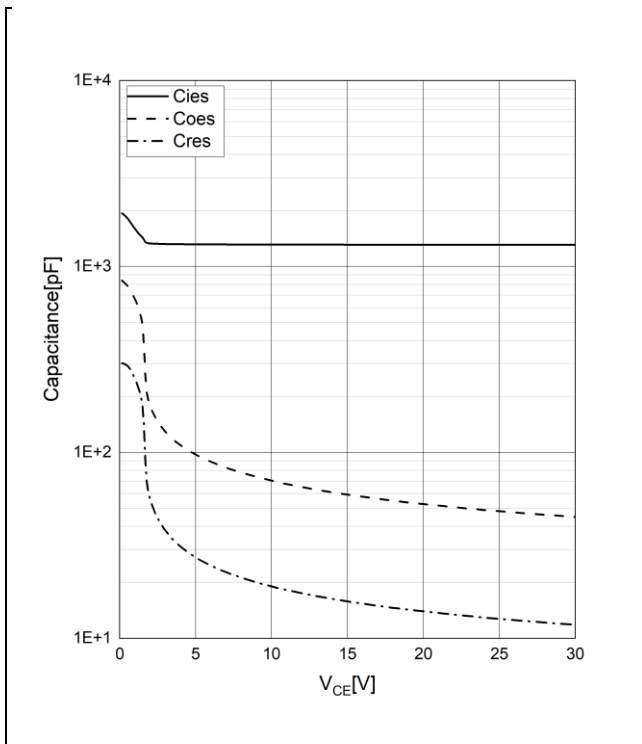


Fig. 8 Diode forward current as a function of forward voltage V_F vs. I_F

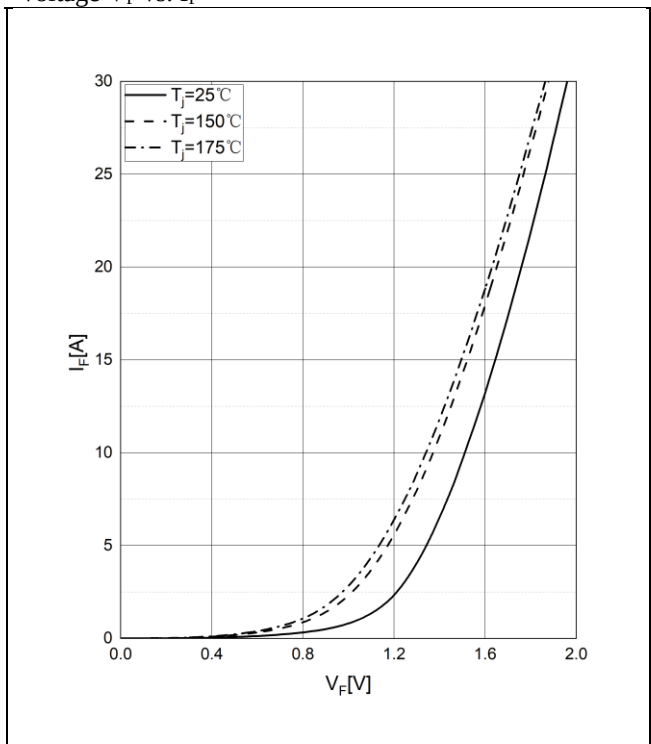


Fig. 9 Diode forward voltage as a function of junction temperature V_F vs. T_j

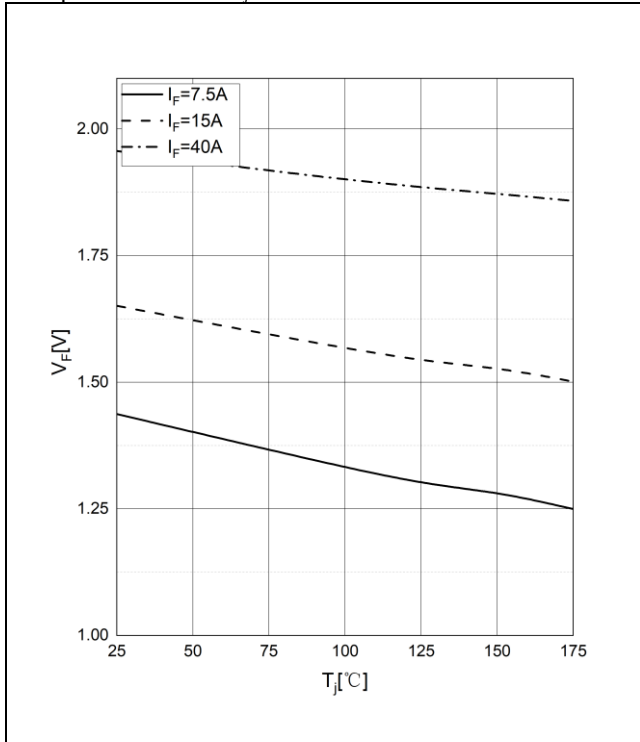


Fig. 10 Switching times vs. Collector current I_C

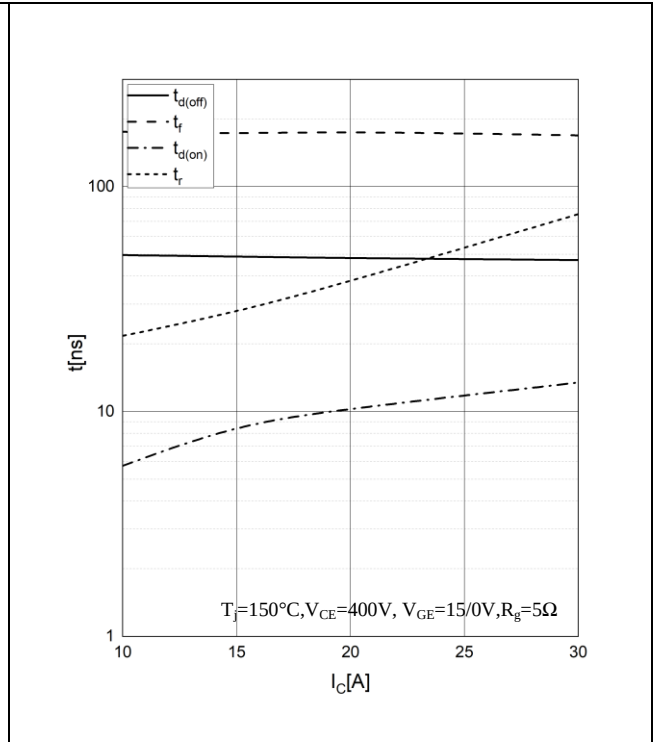


Fig. 11 Switching times vs. Gate resistor R_g

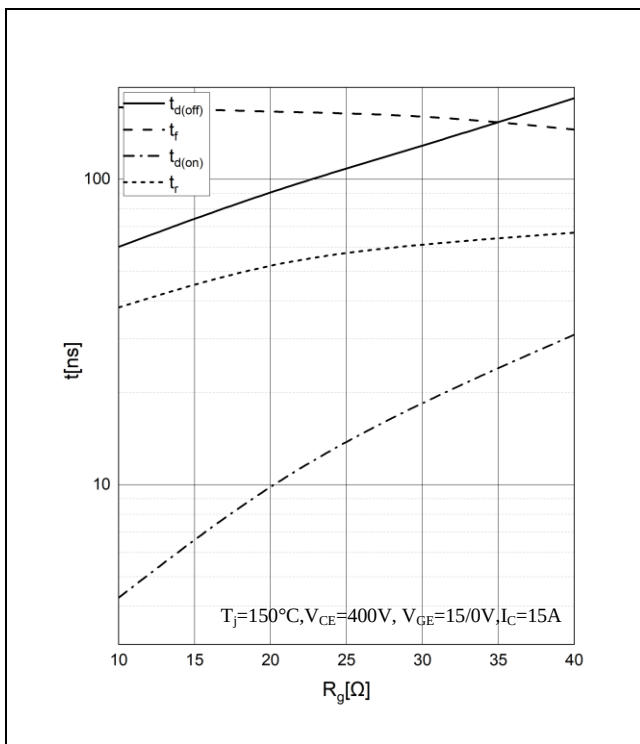


Fig. 12 Switching times vs. Junction temperature T_j

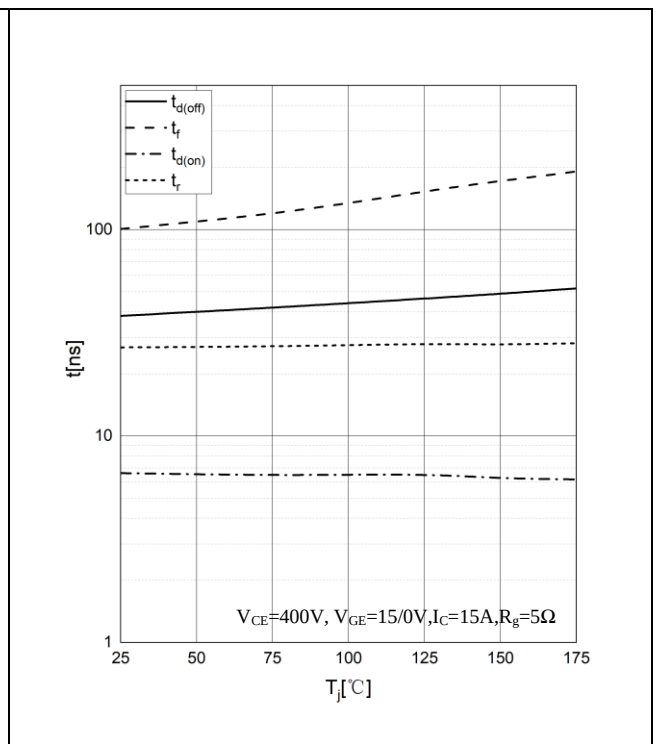


Fig. 13 Switching energy loss vs. Collector current I_C

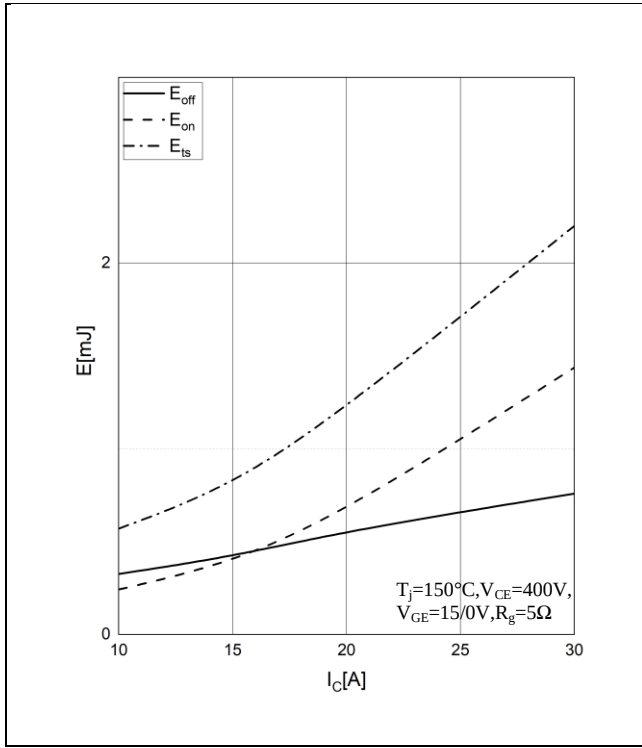


Fig. 14 Switching energy loss vs. Gate resistor R_g

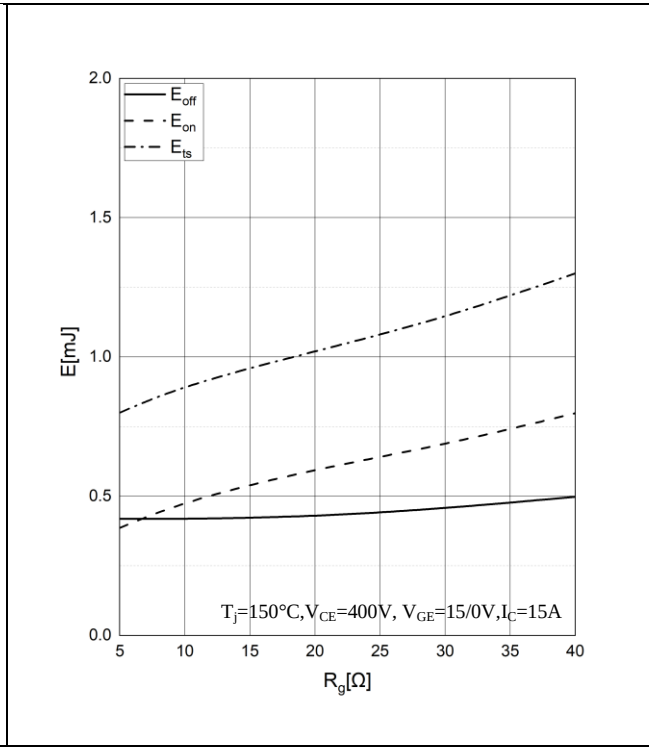


Fig. 15 Switching energy loss vs. Junction temperature T_J

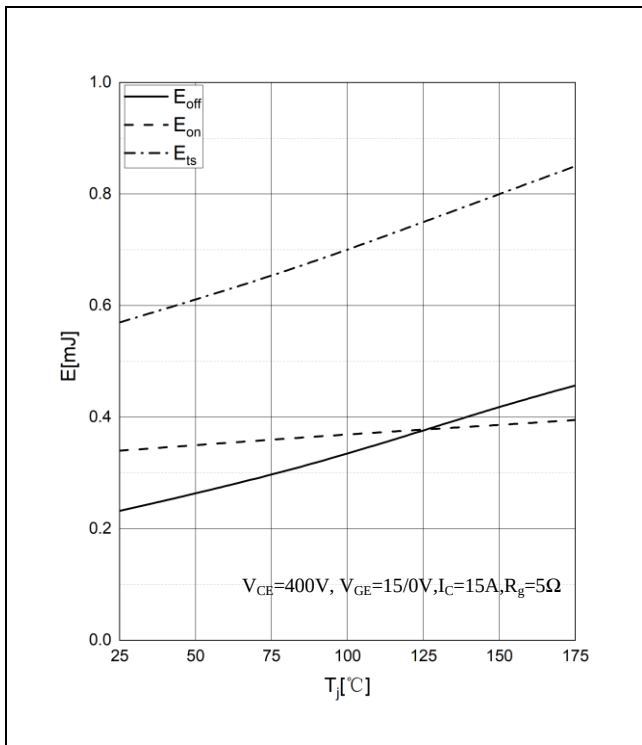


Fig. 16 Switching energy loss vs. Collector-emitter voltage V_{CE}

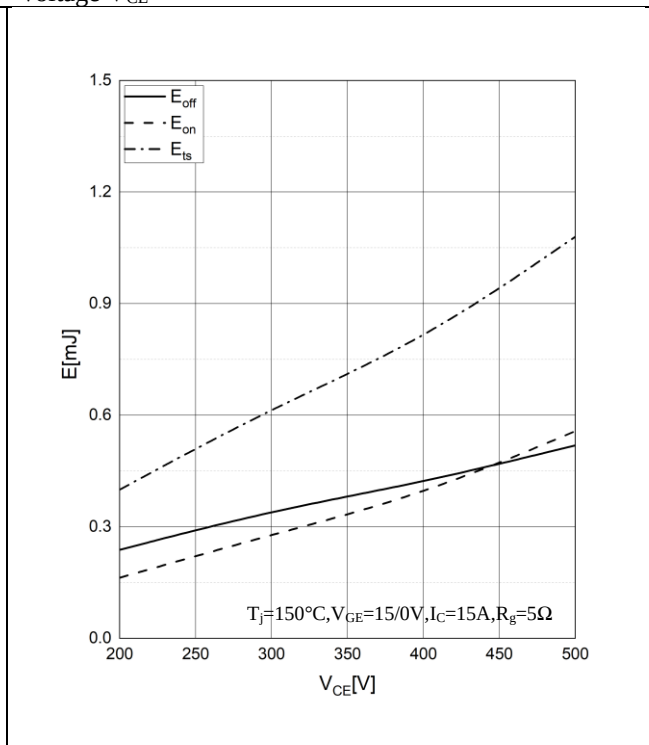


Fig. 17 Reverse recovery times as a function of diode current slope t_{rr} vs. di_F/dt

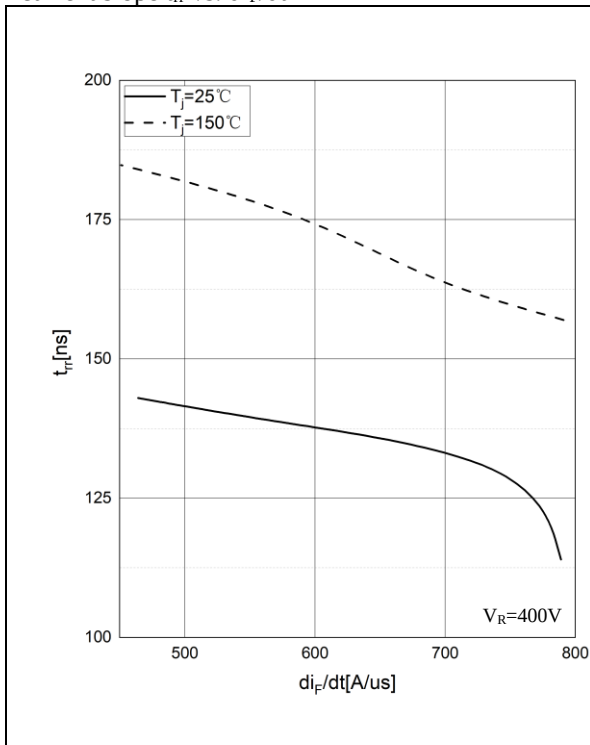


Fig. 18 Reverse recovery charge as a function of diode current slope Q_{rr} vs. di_F/dt

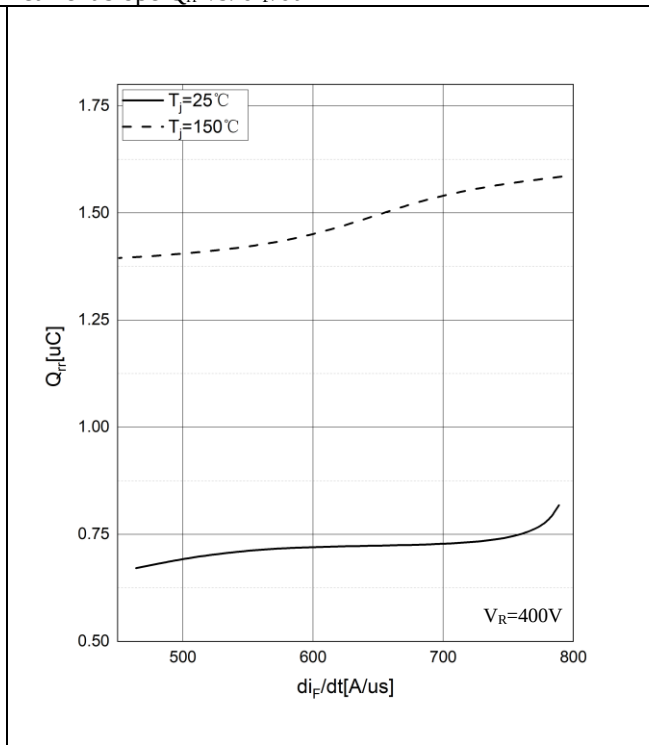


Fig. 19 Reverse recovery current as a function of diode current slope I_{rr} vs. di_F/dt

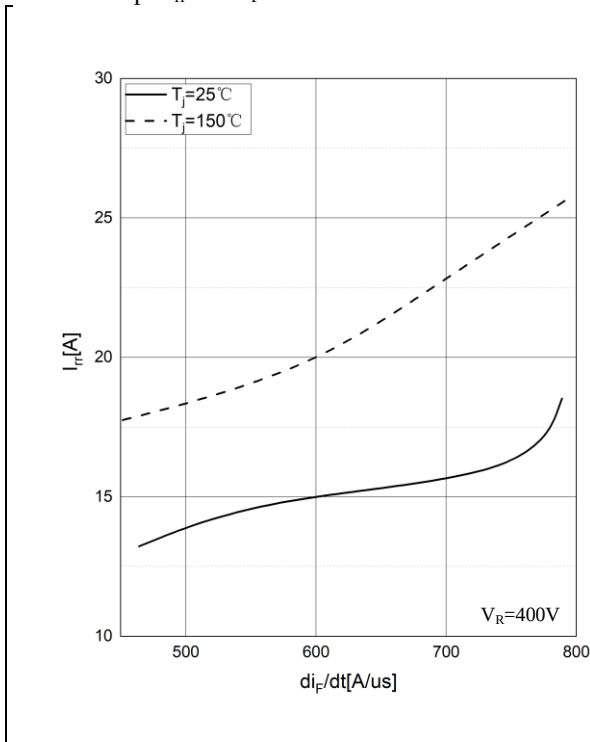


Fig. 20 Reverse recovery energy as a function of diode current slope E_{rr} vs. di_F/dt

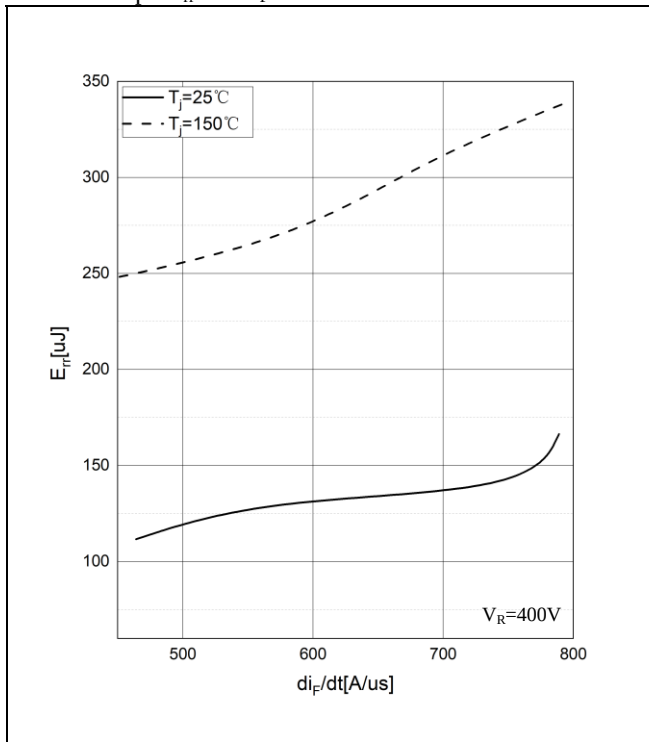


Fig. 21 FBSOA characteristic for TO220

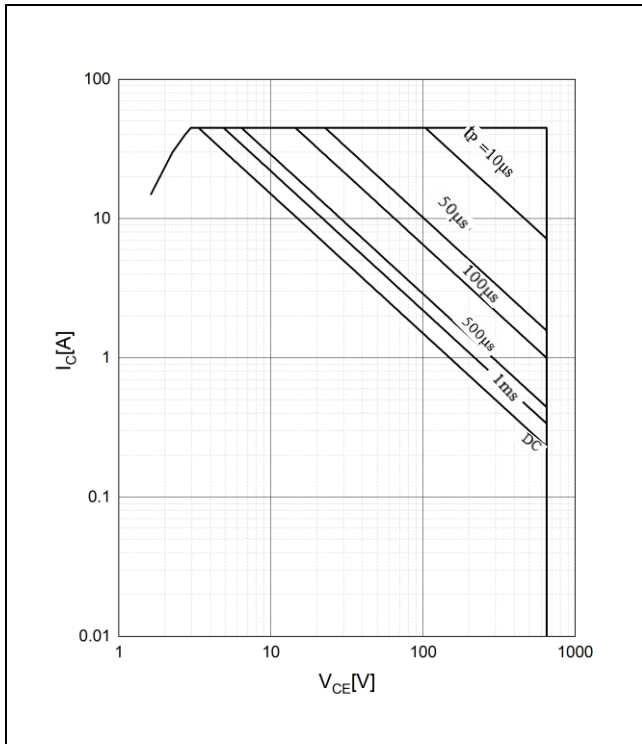


Fig. 22 FBSOA characteristic for TO220F

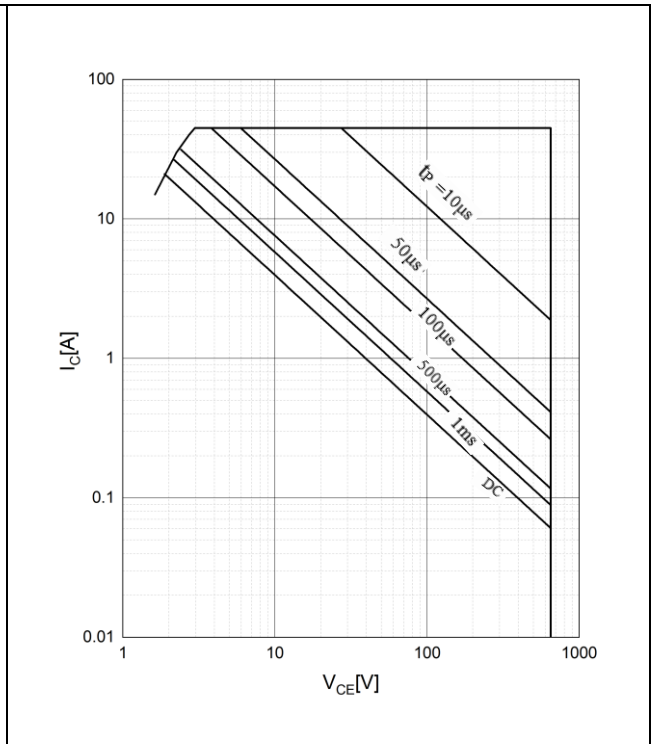


Fig. 23 IGBT transient thermal impedance Z_{thjc} for TO220

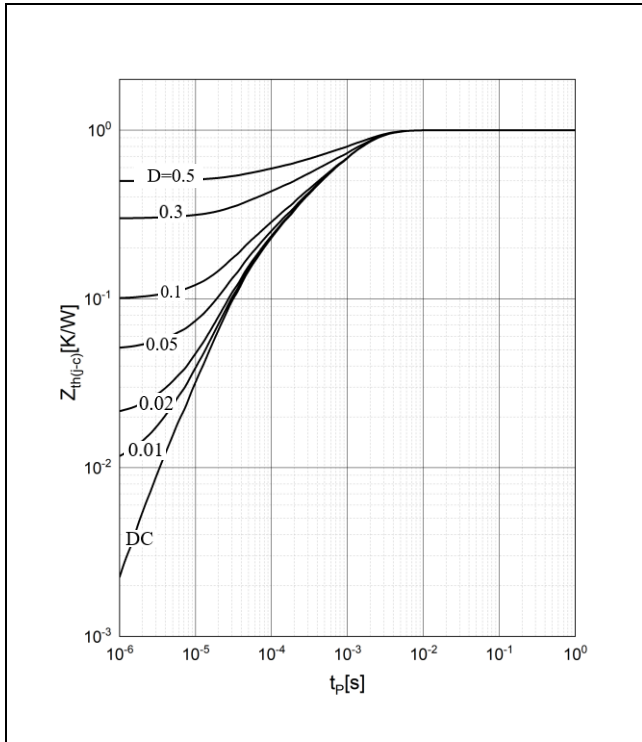


Fig. 24 IGBT transient thermal impedance Z_{thjc} for TO220 F

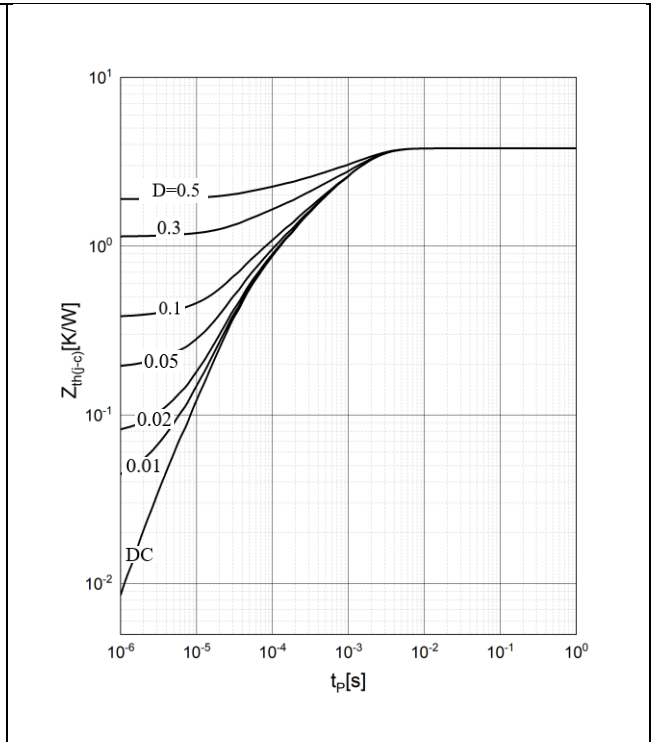


Fig. 25 Diode transient thermal impedance Z_{thjc} for TO220

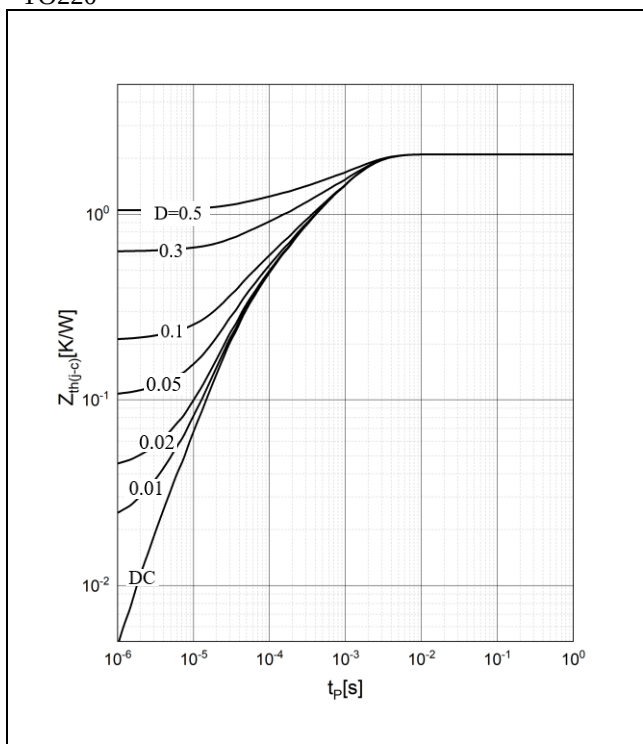


Fig. 26 Diode transient thermal impedance Z_{thjc} for TO220F

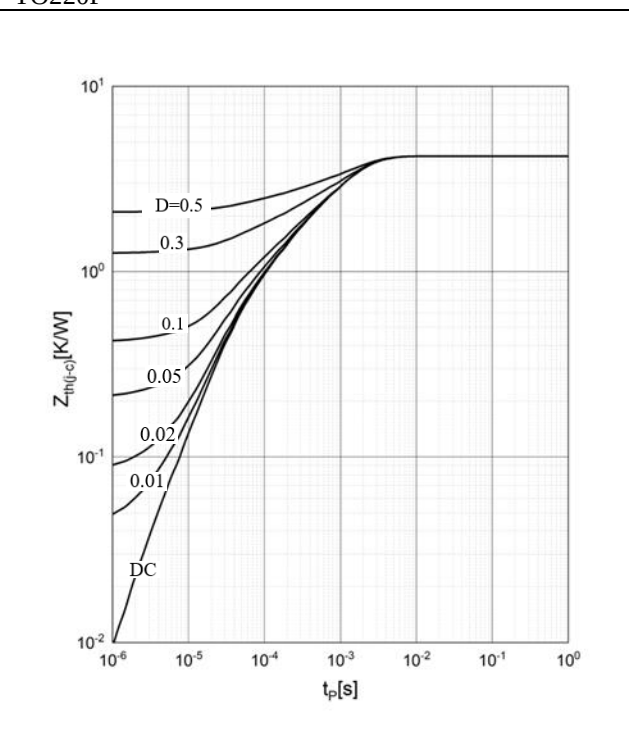


Fig. 27 Power dissipation as a function of case temperature P_{tot} vs. T_c for TO220

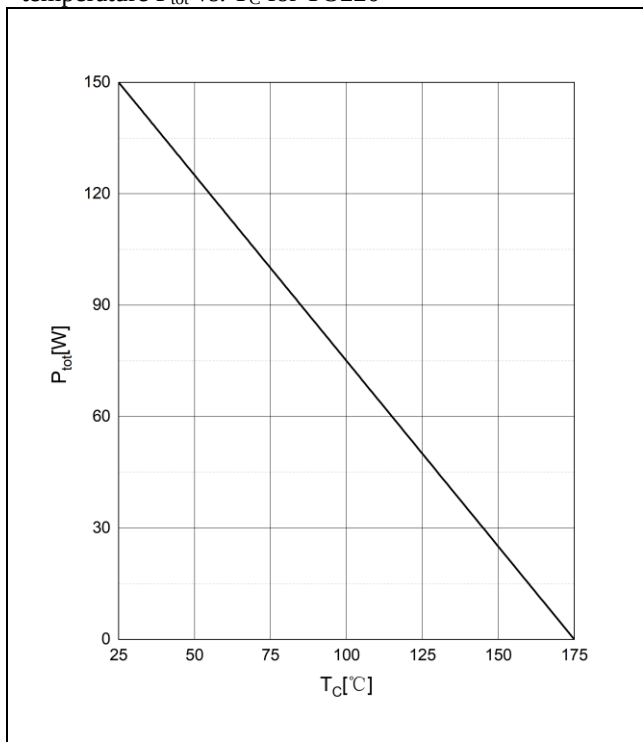
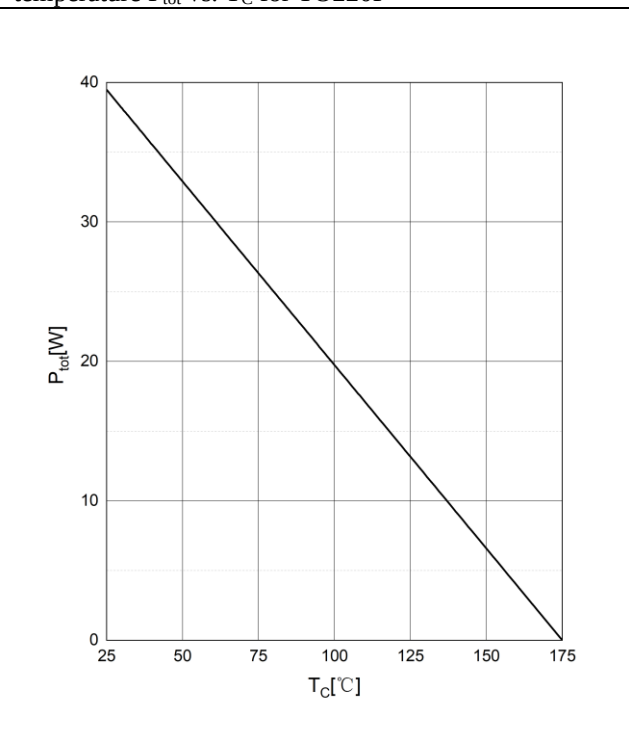
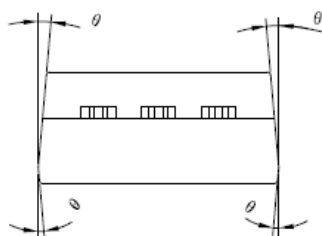
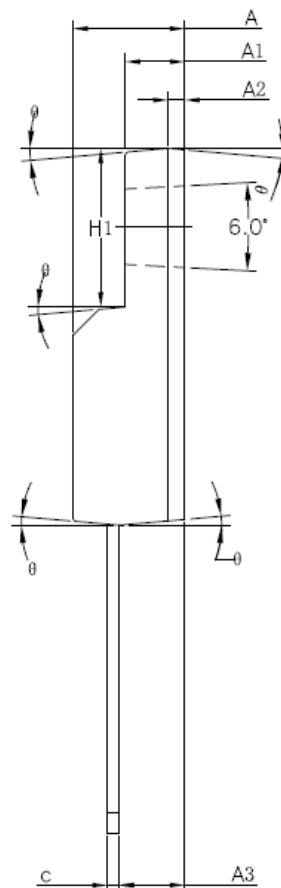
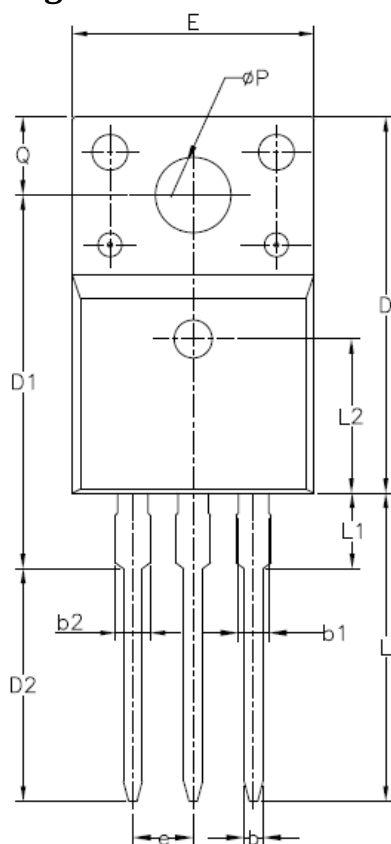


Fig. 28 Power dissipation as a function of case temperature P_{tot} vs. T_c for TO220F

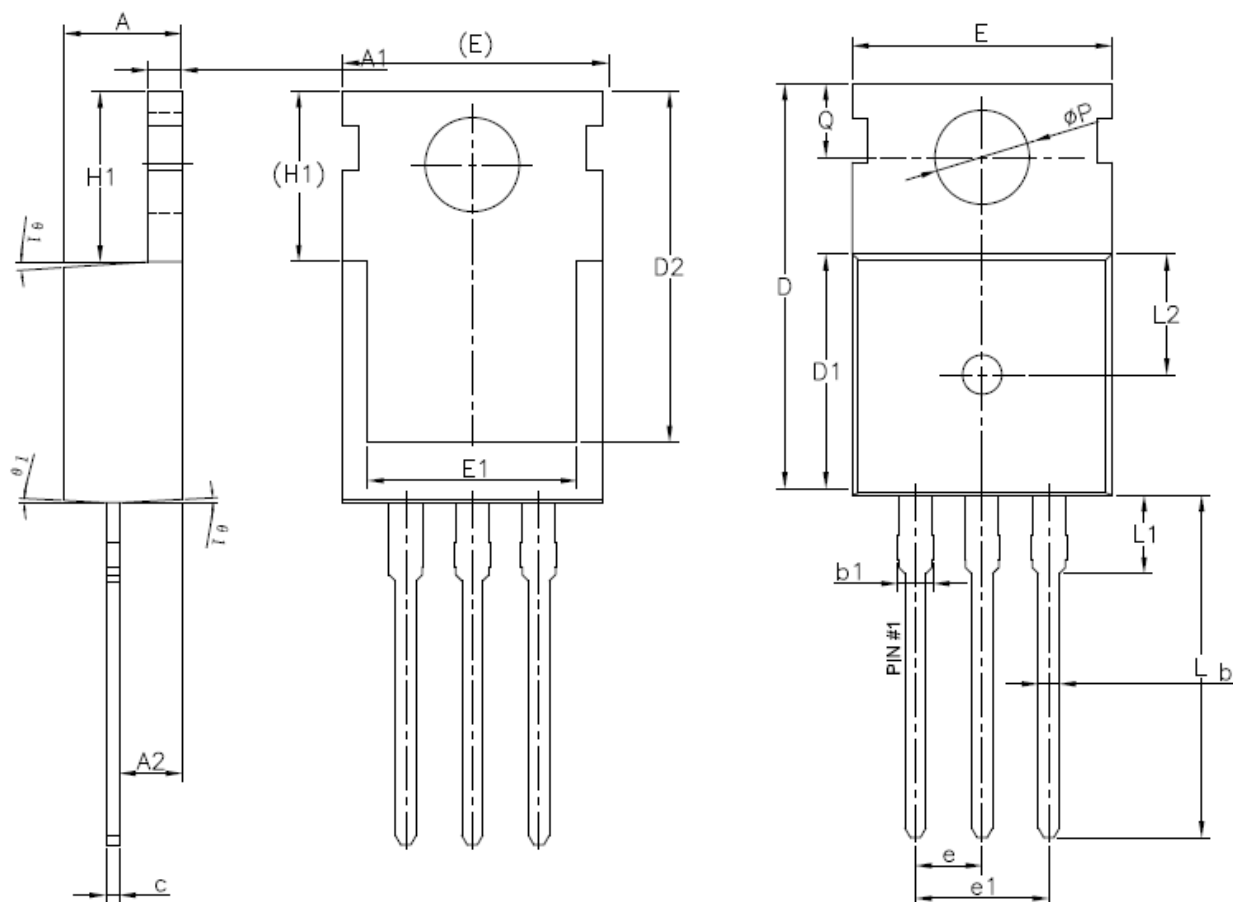


TO-220F package information

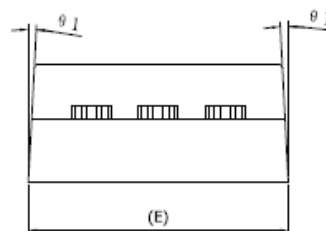


SYMBOL	MIN	NOM	MAX
A	4.50	4.70	4.83
A1	2.34	2.54	2.74
A2	0.70 REF		
A3	2.56	2.76	2.93
b	0.70	—	0.90
b1	1.18	—	1.38
b2	—	—	1.47
c	0.45	0.50	0.60
D	15.67	15.87	16.07
D1	15.55	15.75	15.95
D2	9.60	9.80	10.0
E	9.96	10.16	10.36
e	2.54BSC		
H1	6.48	6.68	6.88
L	12.68	12.98	13.28
L1	—	—	3.50
L2	6.50REF		
ϕP	3.08	3.18	3.28
Q	3.20	—	3.40
θ_1	1°	3°	5°

TO-220 package information



SYMBOL	MIN	NOM	MAX
A	4.40	4.50	4.60
A1	1.27	1.30	1.33
A2	2.30	2.40	2.50
b	0.70	—	0.90
b1	1.27	—	1.40
c	0.45	0.50	0.60
D	15.30	15.70	16.10
D1	9.10	9.20	9.30
D2	13.10	—	13.70
E	9.70	9.90	10.20
E1	7.80	8.00	8.20
e	2.49	2.54	2.59
e1	5.03	5.08	5.12
H1	6.30	6.50	6.70
L	12.78	13.08	13.38
L1	3.30	—	3.50
L2	4.50	4.60	4.70
ϕP	3.55	3.60	3.65
Q	2.73	—	2.87
θ_1	1°	3°	5°



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